

Notice of References Cited	Application/Control No. 09/882,534	Applicant(s)/Patent Under Reexamination DERDERIAN ET AL.	
	Examiner Toniae M. Thomas	Art Unit 2822	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0153579 A1	10-2002	Yamamoto, Ichiro	257/412
*	B	US-2002/0182820 A1	12-2002	Choi et al.	438/396
*	C	US-2002/0197744 A1	12-2002	Lee, Kyu-Mann	438/3
*	D	US-2004/0018747 A1	01-2004	Lee et al.	438/761
*	E	US-2004/0125541 A1	07-2004	Chung, Hyun-Jin	361/306.3
*	F	US-2005/0082593 A1	04-2005	Lee et al.	257/306
*	G	US-6,849,505 B2	02-2005	Lee et al.	438/261
*	H	US-6,946,342 B2	09-2005	Yeo et al.	438/240
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002-222934 A	08-2002	Japan	Iizuka et al.	H01L 27/108
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.